

## **REMARKS**

Claims 1-35 remain pending in the application. Claims 1, 11, 12, 13, 22, 26, 27, 29, 30, 31, and 35 have been amended. Applicant notes that support for the features amended into the independent claims can be found at various points in the specification, such as in the paragraph beginning on page 6, line 19.

### **Objections to the Specification:**

The specification was objected to for various informalities. Applicant has amended the specification to correct these informalities, and submits that the various objections have been overcome.

### **35 U.S.C. § 112 Rejection:**

Claims 26, 27, 29-31, and 35 were rejected under 35 U.S.C. § 112, second paragraph, as being indefinite for failing to point out and distinctly claim the subject matter Applicant regards as the invention. In particular, claims 26, 27, 29-31, and 35, which are method claims, were rejected due to inconsistency with various ones of the device claims. Applicant has amended claims 26, 27, 29-31, and 35 and submits that these amended claims are consistent with the device claims in the application. Applicant has also amended claim 22 to maintain this consistency. Accordingly, Applicant respectfully requests removal of the § 112 rejection.

### **35 U.S.C. § 102 and § 103 Rejections:**

Claims 22 and 23 were rejected under 35 U.S.C. § 102(b) as being anticipated by Motika, U.S. Patent 5,982,189. Claims 1, 2, 4, 6, 9-15, 19, 21, and 31-34 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Au, U.S. Patent 6,681,359, in view of Motika. Claims 16 and 17 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Au in view of Motika and in further view of Arimilli, U.S. Patent 6,665,828 and Das, "Reducing Test Data Volume using External/LBIST Hybrid Test Patterns", ITC Test Conference 2000. Claim 18 was rejected under 35 U.S.C. § 103(a) as being unpatentable over Au in view of Motika and in further view of Koproski, U.S. Patent

6,671,838. Claims 3 and 20 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Au in view of Motika and in further view of Krishna, U.S. Patent 6,000,048. Claims 24 and 24 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Motika and in view of Krishna. Claims 26-29 and 35 were rejected under 35 U.S.C. § 103(a) as being unpatentable over Motika in view of Krishna. Claim 30 was rejected under 35 U.S.C. § 103(a) as being unpatentable over Motika in view of Lo, U.S. Patent 5,661,732. Applicant respectfully traverses these rejections.

With regard to the § 102 rejection, Applicant submits that **the cited reference does not teach all of the elements of independent claim 22**. Motika teaches a built-in stress circuit for an integrated circuit that has a frequency generator, at least one self-test circuit, a temperature regulator and a controller. The frequency generator receives a reference clock and an adjusted temperature frequency from the temperature regulator and outputs the test frequencies needed for the self-test circuits. The self-test circuits, which are coupled to the frequency generator, receive the test frequencies and dissipate power as the self-test circuits are being used. The temperature regulator, which is coupled to the self-test circuits and the frequency generator, senses the power dissipated (i.e., the temperature), adjusts a temperature frequency corresponding to the temperature desired, and outputs the adjusted temperature frequency. The controller, which is coupled to the frequency generator, the self-test circuits, and the temperature regulator, provides the control data necessary for testing both electrical and thermal stress conditions.

In contrast, independent claim 22 recites, in pertinent part:

“A method for use in performing a built-in self-test, the method comprising ... wherein the built-in self-test is performed by a built-in self-test controller that is geographically centralized in an integrated circuit” (Emphasis added).

Motika does not teach or suggest this combination of features. In particular, Applicant can find no teaching or suggestion in Motika of a built-in self-test controller

that is geographically centralized in an integrated circuit, as recited in claim 22. Accordingly, Applicant submits that Motika does not anticipate claim 22, and therefore respectfully requests removal of the 35 U.S.C. § 102(b) rejection.

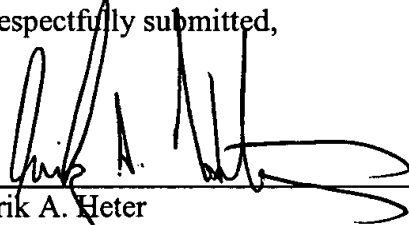
With regard to the 35 U.S.C. § 103(a) rejections, Applicant notes that independent claims 1, 13, and 31 recite combinations of features similar to that recited in claim 22. Thus, for at least the reasons stated above with regard to the 35 U.S.C. § 102(b) rejection, Applicant submits that the cited references, taken singly or in combination, do not teach or suggest all of the elements of the independent claims. In particular, Applicant can find no teaching or suggestion in any of the cited references of a built-in self-test controller that is geographically centralized in an integrated circuit. Accordingly, removal of the 35 U.S.C. § 103(a) rejections is respectfully requested.

**CONCLUSION**

Applicant submits the application is in condition for allowance, and an early notice to that effect is requested.

If any fees are due, the Commissioner is authorized to charge said fees to Meyertons, Hood, Kivlin, Kowert, & Goetzel, P.C. Deposit Account No. 501505/5681-55200/BNK.

Respectfully submitted,



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